

| L Number | Hits | Search Text  | DB  | Time stamp       |
|----------|------|--|---|------------------|
| -        | 967  | (BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/03/19 15:01 |
| -        | 281  | ((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache) ) and ((ATE "automatic test equipment" tester) and (flip-flop latch selector "flip flop" flipflop "shift register"))   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/03/19 14:54 |
| -        | 365  | ((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)).ti. ((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)).ab.  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/03/19 15:05 |
| -        | 300  | ((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache) ) and (buffer and control\$3 and (selector flip-flop latch selector "flip flop" flipflop "shift register"))  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/03/19 15:07 |
| -        | 163  | ((((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache) ) and ((ATE "automatic test equipment" tester) and (flip-flop latch selector "flip flop" flipflop "shift register")))) and (buffer and control\$3 and (selector flip-flop latch selector "flip flop" flipflop "shift register")) | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/03/21 10:40 |
| -        | 2    | 5235600.pn.  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2003/03/21 10:45 |